


<b>Search Notes</b>  	<b>Application/Control No.</b>  10539310	<b>Applicant(s)/Patent Under Reexamination</b>  KWON ET AL.
	<b>Examiner</b>  Ley, Francisco M	<b>Art Unit</b>  3746

SEARCHED			
Class	Subclass	Date	Examiner
417	416, 417, DIG1	8/13/07	FML
252	67, 68, 69	8/13/07	FML
418	100	8/13/07	FML

SEARCH NOTES			
Search Notes		Date	Examiner
NPL search on Google and SCIRUS		9/04/07	FML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner